

Notice of References Cited	Application/Control No. 10/083,991	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,365,523	04-2002	Jang et al.	438/692
*	B	US-5,728,621	03-1998	Zheng et al.	438/427
*	C	US-6,287,174	09-2001	Detzel et al.	451/41
*	D	US-6,461,932	10-2002	Wang, Fu-Cheng	438/400
*	E	US-6,511,576	01-2003	Klein, Rita J.	216/89
*	F	US-6,171,962	01-2001	Karlsson et al.	438/692
*	G	US-6,090,714	07-2000	Jang et al.	438/692
*	H	US-6,436,833	08-2002	Pang et al.	438/692
*	I	US-6,117,798	09-2000	Fang et al.	438/782
*	J	US-5,173,439	12-1992	Dash et al.	438/424
*	K	US-6,524,950	02-2003	Lin, Bih-Tiao	438/644
*	L	US-6,287,174	09-2001	Detzel et al.	451/41
*	M	US-5,362,669	11-1994	Boyd et al.	438/437

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0203634	10-2003	Homma et al.	438/692
*	B	US-5,851,899	12-1998	Weigand, Peter	438/427
*	C	US-2003/0203633	10-2003	Sinha, Nishant	438/692
*	D	US-6,383,933	05-2002	Shu et al.	438/692
*	E	US-5,494,857	02-1996	Cooperman et al.	438/437
*	F	US-6,255,161	07-2001	Lin, Wei-Ray	438/254
*	G	US-6,455,428	09-2002	Tseng, Horng-Huei	438/689
*	H	US-5,077,234	12-1991	Scoopó et al.	438/427
*	I	US-6,489,216	12-2002	Shiu et al.	438/401
*	J	US-6,004,653	12-1999	Lee, Chen-tsai	428/141
*	K	US-2001/0006761	07-2001	GOLZ et al.	430/311
*	L	US-6,221,560	04-2001	Soo et al.	430/311
*	M	US-6,613,690	09-2003	Chang et al.	438/712

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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NON-PATENT DOCUMENTS

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	W	
	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,420,226	07-2002	Chen et al.	438/238
*	B	US-6,461,932	10-2002	Wang, Fu-Cheng	438/400
*	C	US-5,126,006	06-1992	Cronin et al.	438/702
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2002270688 A	09-2002	Japan	KONO, HIROYUKI	H01L 21/768
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Stanley Wolf, Silicon Processing for VLSI Era, Lattice Press, Volume II, 20-22, 45-46, and 49
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.